## AMENDMENTS TO THE CLAIMS

- 1. (currently amended) A method of fabricating a solar cell, the method comprising: etching a first layer comprising copper without substantially etching a topmost metallic layer comprising tin on a backside of a solar cell, the topmost metallic layer providing a solderable metallic surface for electrically coupling the solar cell to an external electrical circuit.
- 2. (canceled)
- 3. (original) The method of claim 1 wherein the first layer is etched using an etchant comprising sulfuric acid and hydrogen peroxide.
- 4. (original) The method of claim 1 wherein the first layer is etched using an etchant comprising about 1% by volume of sulfuric acid, about 4% by volume of phosphoric acid, and about 2% by volume of stabilized hydrogen peroxide.
- 5. (original) The method of claim 1 wherein the first layer is etched using a Co-Bra Etch® etchant.
- 6. (original) The method of claim 5 wherein the Co-Bra Etch<sup>®</sup> etchant is modified to comprise about 1% by volume of sulfuric acid, about 4% by volume of phosphoric acid, and about 2% by volume of stabilized hydrogen peroxide.
- 7. (original) The method of claim 1 wherein the first layer is etched using a Perma-Etch ® etchant.
- 8. (original) The method of claim 1 wherein the topmost metallic layer comprises tin and the first layer is etched using an etchant comprising sulfuric acid and hydrogen peroxide.
- 9. (original) The method of claim 1 further comprising:
  etching a second layer comprising titanium-tungsten using an etchant comprising hydrogen peroxide.
- 10. (original) The method of claim 9 further comprising:
  etching a third layer comprising aluminum using an etchant comprising potassium hydroxide.
- 11. (original) The method of claim 1 further comprising:
  etching a second layer comprising aluminum using an etchant comprising potassium hydroxide.
- 12. (original) The method of claim 11 wherein the etchant comprises about 1% by volume of potassium hydroxide in water.

13. (currently amended) A method of etching a layer of material in a solar cell, the method comprising:

etching a copper layer selective to a tin layer on a backside of a solar cell using an etchant comprising sulfuric acid and hydrogen peroxide.

- 14. (original) The method of claim 13 wherein the etchant comprises about 1% by volume of sulfuric acid, about 4% by volume of phosphoric acid, and about 2% by volume of stabilized hydrogen peroxide.
- 15. (original) A method of etching a layer of material in a solar cell, the method comprising:

etching a metal layer without substantially etching a tin layer of a solar cell.

- 16. (original) The method of claim 15 wherein the metal layer comprises copper.
- 17. (original) The method of claim 15 wherein the metal layer comprises copper etched using an etchant comprising about 1% by volume of sulfuric acid, about 4% by volume of phosphoric acid, and about 2% by volume of stabilized hydrogen peroxide.
- 18. (original) The method of claim 15 wherein the metal layer comprises copper etched using an etchant comprising hydrogen peroxide and sulfuric acid.
- 19. (original) The method of claim 15 wherein the metal layer comprises aluminum.
- 20. (original) The method of claim 15 wherein the metal layer comprises aluminum etched using an etchant comprising potassium hydroxide.
- 21. (original) The method of claim 15 wherein the metal layer comprises aluminum etched using an etchant comprising about 1% by volume of potassium hydroxide in water.
- 22. (original) A method of etching a layer of material in a solar cell, the method comprising:

etching an aluminum layer selective to a tin layer using an etchant comprising potassium hydroxide.

23. (original) The method of claim 22 wherein the etchant comprises about 1% by volume of potassium hydroxide in water.

## 24-27 (canceled)

28. (original) A method of fabricating a solar cell, the method comprising:
etching a first layer comprising aluminum without substantially etching a
topmost metallic layer of a solar cell.

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- 29. (original) The method of claim 28 wherein the topmost metallic layer comprises tin.
- 30. (original) The method of claim 28 wherein the first layer is etched using an etchant comprising potassium hydroxide.
- 31. (original) The method of claim 30 wherein the etchant comprises about 1% by volume of potassium hydroxide in water.
- 32. (original) The method of claim 28 wherein the first layer is etched using an etchant that is selective to an oxide layer under the first layer.